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Controlling the Solder Joint Reliability of eWLB Packages in Automotive Radar Applications Using a Design for Reliability Approach

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#### Agenda



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#### Agenda





## Background: Automotive RADAR



The solder joint reliability of an assembly characteristic to automotive RADAR applications is analyzed



#### Background: Automotive RADAR





Source: M. Eichhorst et al., VII. SGW-Forum, 2019



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## Motivation: Solder joint reliability

 The major part of fails in the considered class of products/assemblies is related to deltas/changes in temperature



Source: M. Eichhorst *et al.*, VII. SGW-Forum, 2019



## Motivation: Solder joint reliability



- CTE mismatch between package and PCB induces stress
- There is no layer at package side which could absorb stress

Source: M. Eichhorst *et al.*, VII. SGW-Forum, 2019

Temperature



## Motivation: Previous findings



 The solder joint reliability (SJR) of eWLB packages for automotive radar is sensitive to the RF laminate

(see Haubner et al., Microelectronics Reliability 2016)



# **Objectives**



- > SJR of eWLB for automotive radar is sensitive to the RF laminate
- > Objectives of this work regarding solder joint reliability:
  - Analyze the sensitivity to the RF laminate
  - Enable Design for Reliabilty (DfR) approach
  - Enable Product to System (P2S) design approach

#### Agenda







## **Predicting Solder Joint Fatigue**



- A simulation framework from literature (Darveaux 1997, Syed 1997) is used to assess solder joint fatigue in a qualitative way
- > Different materials and conditions can be compared relatively



## **Analyzing Sensitivities: MOP and CoP**



- The software optiSLang© is used to systematically explore the multi-parameter design spaces with a minimum of samples
- Metamodeling is used to analyze and rank the sensitivity w.r.t. the investigated parameters

#### Agenda





## Studies #A,#B,#C Setup



- The studies #A,#B and #C presented in the next slides have the following setup:
  - All geometry and material properties are constant
  - The variables are:
    - Study #A & #B: Mechanical properties of RF laminate
    - Study #C: Same as #A, but with PCB constraints added



## **Study #A**: Linear-elastic (1/2) Constant E and CTE





## **Study #A**: Linear-elastic (2/2) Constant E and CTE





#### Interpretation of findings:

- For low CTE, the RF laminate generates a "CTE transition" between the PCB and the package
- For low E modulus, the RF laminate becomes a "buffer layer"

## **Study #B**: Linear-visco-elastic (1/2) Coupled E and CTE



Modulus [GPa]



- Low damage when RF laminate has:
  - Low modulus E (below Tg)
  - and/or low CTE (below Tg)
- Modulus reduction has only impact of 2<sup>nd</sup> order



CTE [ppm/K]

## **Study #B**: Linear-visco-elastic (2/2) Coupled E and CTE





## **Study #C**: Linear-elastic (1/1) External moments @ constant E and CTE





 RF laminates with low Young's modulus further reduce sensitivity w.r.t. external bending of PCB



## **Further findings from sensitivity studies**

- Only little impact of RF laminate layer thicknesses when it varies between 60 µm and 120 µm
  - Consequently, E and CTE of RF laminates are more important
- > RF laminates with **low E modulus** allow better for buffering:
  - Stresses coming from increasing the PCB thickness

For more see: M. Niessner *et al.* "Controlling the solder joint reliability of *eWLB* packages in Automotive RADAR Applications Using a Design for Reliability Approach", ASME InterPACK 2018, 2018

## **Experimental verification:** Sensitivity to E and CTE





- Experiments with the same PCB stack, but different top layer laminates confirm:
  - Lower E modulus allows for longer solder joint life
  - Level of E modulus towards lower temperatures is essential

## **Experimental verification:** Additional buffer layer



- The framework was successfully enabled for quantitative prediction by calibrating a Coffin-Manson-type lifetime model
- Using the calibrated framework, a PCB stack was designed, which allows for improved solder joint reliability even in the presence of a non-optimal RF laminate



#### Agenda







## Summary

- RF laminates with low Young's modulus allow for the highest solder joint reliability on unconstrained and constrained PCBs
- A simulation framework allows for early and predictive Product to System (P2S) assessment of hybrid PCB stacks used with automotive RADAR applications and, thus, Design for Reliability (DfR) in order to ensure that automotive reliability requirements can be met





# Outlook

 Linear-elastic and linear-visco-elastic material modeling of RF laminates may not be sufficient



 Future work will focus on advanced material modeling





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